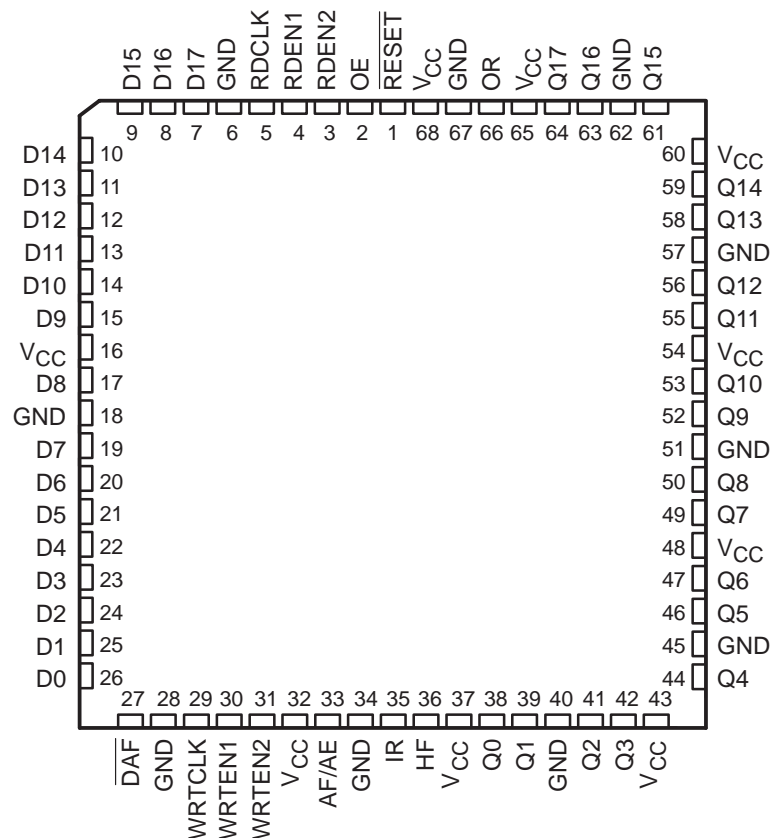




**THE DATASHEET OF
SN74ACT7882-30PN**



- Member of the Texas Instruments Widebus™ Family
- Independent Asynchronous Inputs and Outputs
- Read and Write Operations Can Be Synchronized to Independent System Clocks
- Programmable Almost-Full/Almost-Empty Flag
- Pin-to-Pin Compatible With SN74ACT7881 and SN74ACT7811
- Input-Ready, Output-Ready, and Half-Full Flags
- Cascadable in Word Width and/or Word Depth (See Application Information)
- Fast Access Times of 11 ns With a 50-pF Load
- High Output Drive for Direct Bus Interface
- Package Options Include 68-Pin Plastic Leaded Chip Carriers (FN) or 80-Pin Shrink Quad Flat (PN) Package

FN PACKAGE
(TOP VIEW)

Please be aware that an important notice concerning availability, standard warranty, and use in critical applications of Texas Instruments semiconductor products and disclaimers thereto appears at the end of this data sheet.

Widebus is a trademark of Texas Instruments Incorporated.

PRODUCTION DATA information is current as of publication date. Products conform to specifications per the terms of Texas Instruments standard warranty. Production processing does not necessarily include testing of all parameters.

 **TEXAS
INSTRUMENTS**

POST OFFICE BOX 655303 • DALLAS, TEXAS 75265

Copyright © 1998, Texas Instruments Incorporated

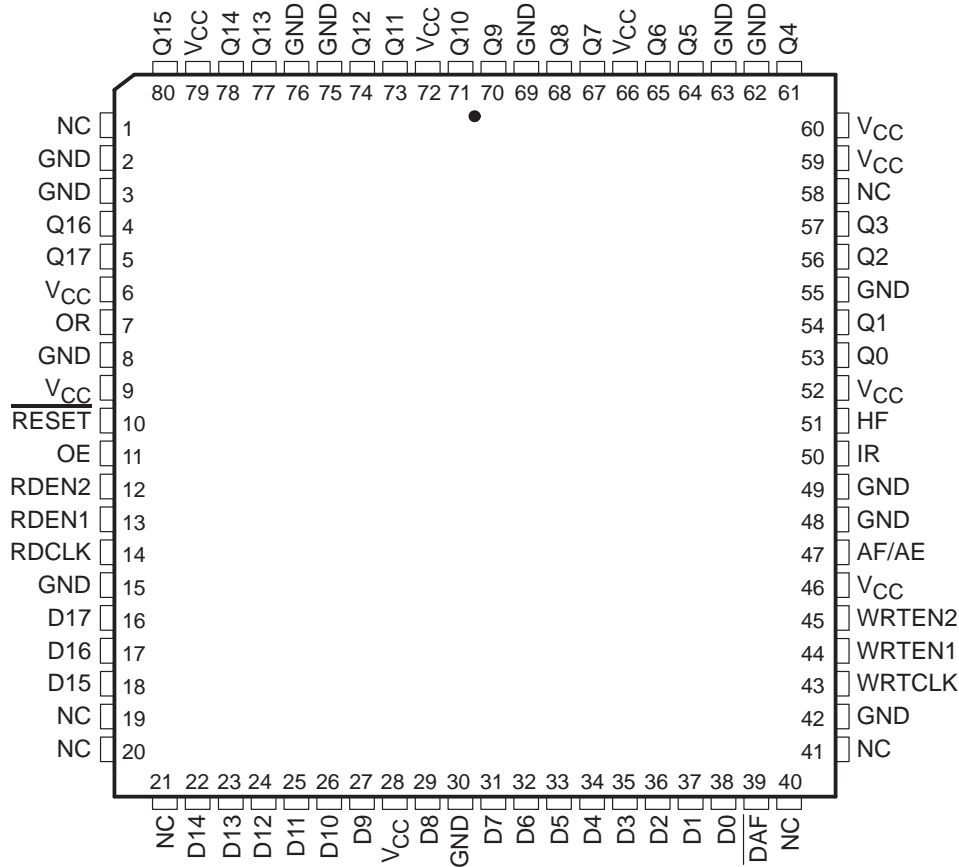
SN74ACT7882

2048 × 18

CLOCKED FIRST-IN, FIRST-OUT MEMORY

SCAS445C – JUNE 1994 – REVISED APRIL 1998

PN PACKAGE
(TOP VIEW)



NC – No internal connection

description

A FIFO memory is a storage device that allows data to be written into and read from its array at independent data rates. The SN74ACT7882 is organized as 2048 bits deep × 18 bits wide. The SN74ACT7882 processes data at rates up to 67 MHz and access times of 11 ns in a bit-parallel format. Data outputs are noninverting with respect to the data inputs. Expansion is accomplished easily in both word width and word depth.

The SN74ACT7882 has normal input-bus to output-bus asynchronous operation. The special enable circuitry adds the ability to synchronize independent reads and writes to their respective system clocks.

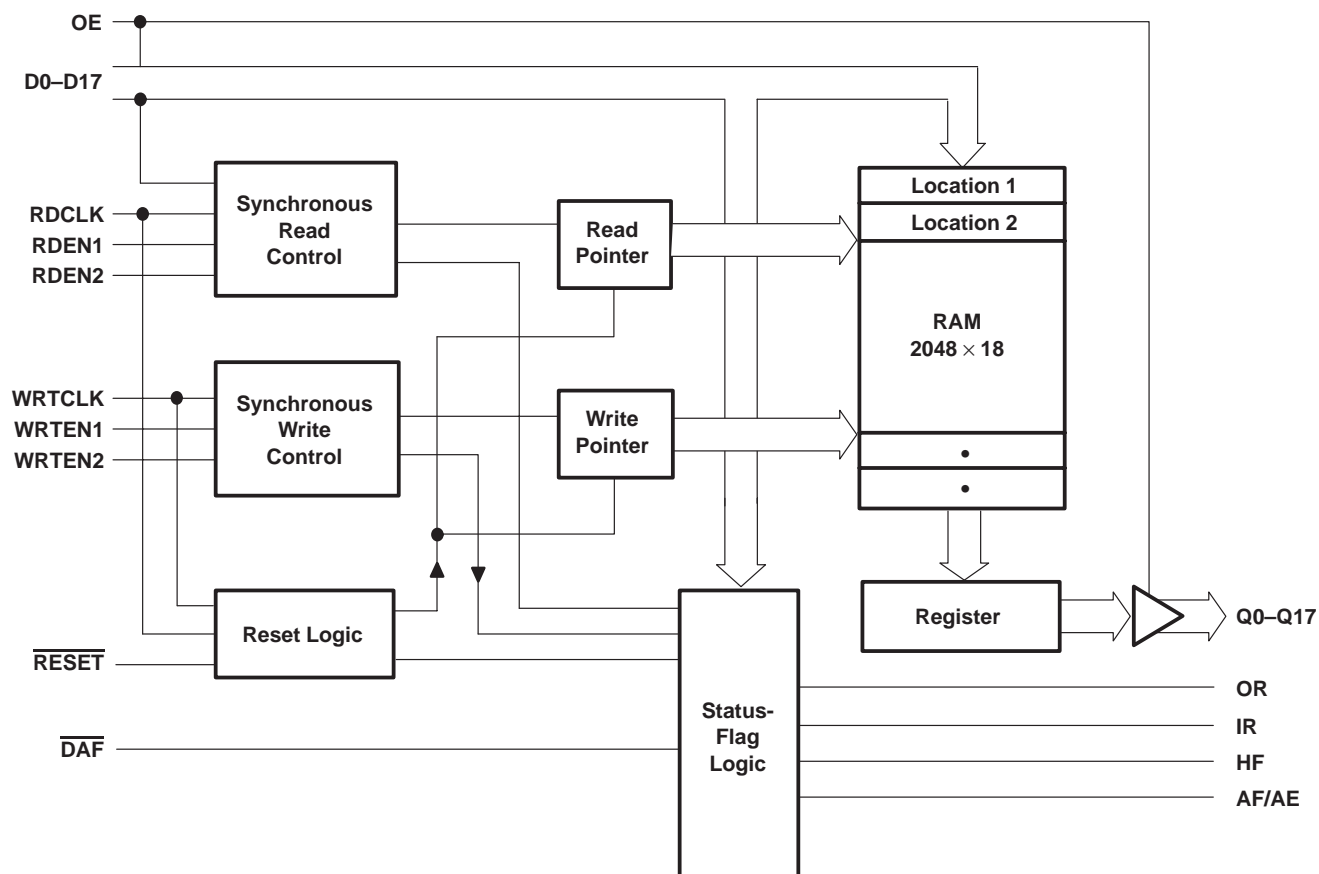
The SN74ACT7882 is characterized for operation from 0°C to 70°C.



SN74ACT7882
2048 × 18
CLOCKED FIRST-IN, FIRST-OUT MEMORY

SCAS445C – JUNE 1994 – REVISED APRIL 1998

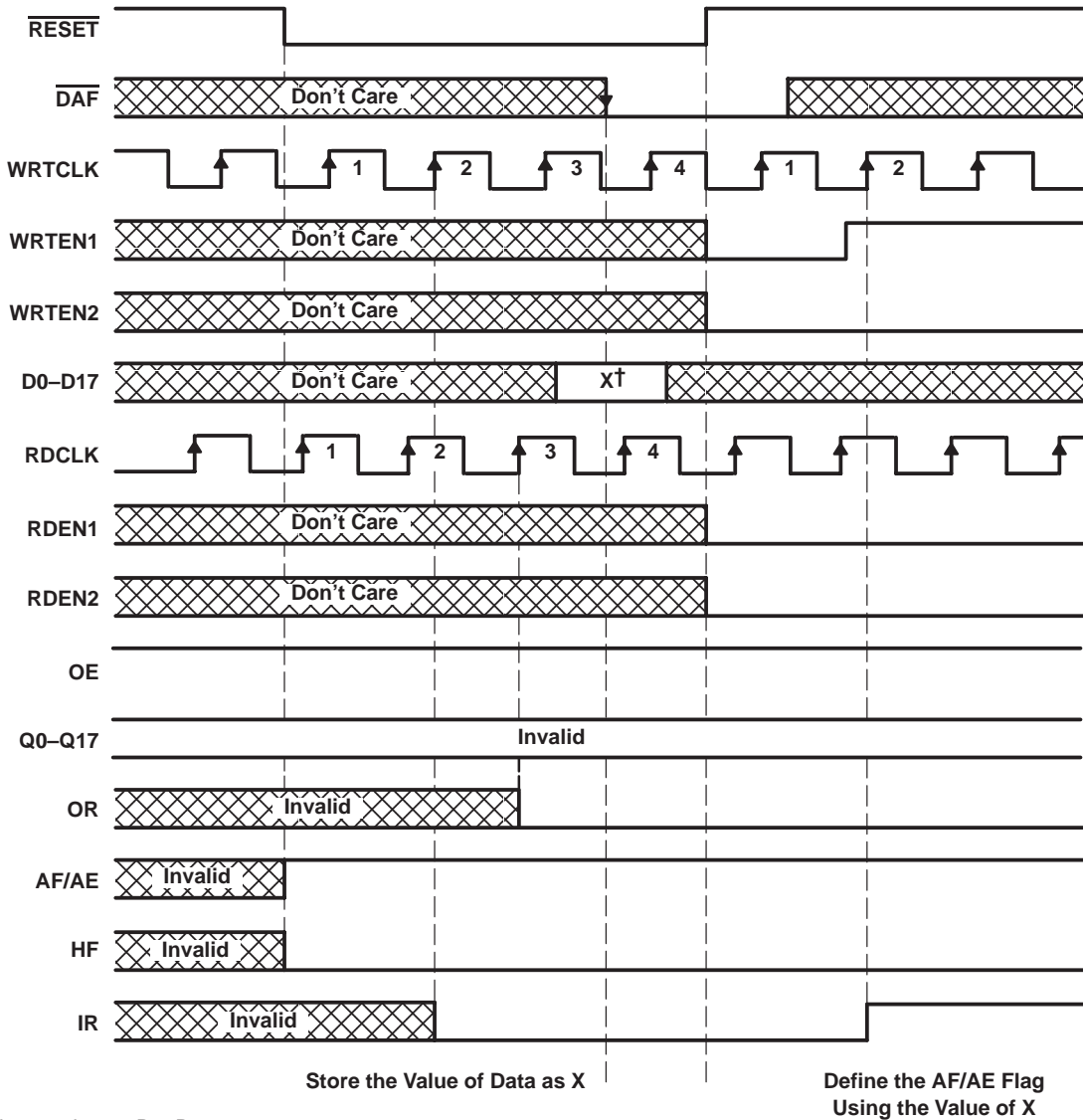
functional block diagram



Terminal Functions†

TERMINAL NAME	NO.	I/O	DESCRIPTION
AF/AE	33	O	<p>Almost-full/almost-empty flag. The AF/AE boundary is defined by the AF/AE offset value (X). This value can be programmed during reset or the default value of 256 can be used. AF/AE is high when the number of words in memory is less than or equal to X. AF/AE also is high when the number of words in memory is greater than or equal to (2048 – X).</p> <p>Programming the AF/AE offset value (X) is accomplished during a reset cycle. The AF/AE offset value (X) is either user-defined or the default value of X = 256. The procedure to program AF/AE is as follows:</p> <p>User-defined X</p> <p>Step 1: Take $\overline{\text{DAF}}$ from high to low. The high-to-low transition of $\overline{\text{DAF}}$ input stores the binary value on the data inputs as X. The following bits are used, listed from most significant bit to least significant bit D9–D0.</p> <p>Step 2: If $\overline{\text{RESET}}$ is not already low, take $\overline{\text{RESET}}$ low.</p> <p>Step 3: With $\overline{\text{DAF}}$ held low, take $\overline{\text{RESET}}$ high. This defines the AF/AE using X.</p> <p>NOTE: To retain the current (X) offset, keep $\overline{\text{DAF}}$ low during subsequent reset cycles.</p> <p>Default X</p> <p>To redefine AF/AE using the default value of X = 256, hold $\overline{\text{DAF}}$ high during the reset cycle.</p>
$\overline{\text{DAF}}$	27	I	Define almost-full. The high-to-low transition of $\overline{\text{DAF}}$ stores the binary value of data inputs as the AF/AE offset value (X). With $\overline{\text{DAF}}$ held low, a $\overline{\text{RESET}}$ cycle defines the AF/AE flag using X.
D0–D17	26–19, 17, 15–7	I	Data inputs for 18-bit-wide data to be stored in the memory. A high-to-low transition on $\overline{\text{DAF}}$ captures data for the almost-empty/almost-full offset (X) from D9–D0.
HF	36	O	Half-full flag. HF is high when the FIFO contains 1024 or more words and is low when the number of words in memory is less than half the depth of the FIFO.
IR	35	O	Input-ready flag. IR is high when the FIFO is not full and low when the device is full. During reset, IR is driven low on the rising edge of the second WRTCLK pulse. IR then is driven high on the rising edge of the second WRTCLK pulse after $\overline{\text{RESET}}$ goes high. After the FIFO is filled and IR is driven low, IR is driven high on the second WRTCLK pulse after the first valid read.
OE	2	I	Output enable. The Q0–Q17 outputs are in the high-impedance state when OE is low. OE must be high before the rising edge of RDCLK to read a word from memory.
OR	66	O	Output-ready flag. OR is high when the FIFO is not empty and low when it is empty. During reset, OR is set low on the rising edge of the third RDCLK pulse. OR is set high on the rising edge of the third RDCLK pulse to occur after the first word is written into the FIFO. OR is set low on the rising edge of the first RDCLK pulse after the last word is read.
Q0–Q17	38–39, 41–42, 44, 46–47, 49–50, 52–53, 55–56, 58–59, 61, 63–64	O	Data out. The first data word to be loaded into the FIFO is moved to Q0–Q17 on the rising edge of the third RDCLK pulse to occur after the first valid write. RDEN1 and RDEN2 do not affect this operation. Following data is unloaded on the rising edge of RDCLK when RDEN1, RDEN2, OE, and OR are high.
RDCLK	5	I	Read clock. Data is read out of memory on the low-to-high transition at RDCLK if OR, OE, and RDEN1 and RDEN2 are high. RDCLK is a free-running clock and functions as the synchronizing clock for all data transfers out of the FIFO. OR also is driven synchronously with respect to RDCLK.
RDEN1 RDEN2	4 3	I	Read enable. RDEN1 and RDEN2 must be high before a rising edge on RDCLK to read a word out of memory. RDEN1 and RDEN2 are not used to read the first word stored in memory.
$\overline{\text{RESET}}$	1	I	Reset. A reset is accomplished by taking $\overline{\text{RESET}}$ low and generating a minimum of four RDCLK and WRTCLK cycles. This ensures that the internal read and write pointers are reset and that OR, HF, and IR are low, and AF/AE is high. The FIFO must be reset upon power up. With $\overline{\text{DAF}}$ at a low level, a low pulse on $\overline{\text{RESET}}$ defines AF/AE using the AF/AE offset value (X), where X is the value previously stored. $\overline{\text{DAF}}$ held high during a $\overline{\text{RESET}}$ cycle defines the AF/AE flag using the default value of X = 256.
WRTCLK	29	I	Write clock. Data is written into memory on a low-to-high transition of WRTCLK if IR, WRTE1, and WRTE2 are high. WRTCLK is a free-running clock and functions as the synchronizing clock for all data transfers into the FIFO. IR also is driven synchronously with respect to WRTCLK.
WRTE1 WRTE2	30 31	I	Write enable. WRTE1 and WRTE2 must be high before a rising edge on WRTCLK for a word to be written into memory. WRTE1 and WRTE2 do not affect the storage of the AF/AE offset value (X).

† Terminals listed are for the FN package.



† X is the binary value on D9–D0.

Figure 1. Reset Cycle: Define AF/AE Using a Programmed Value of X

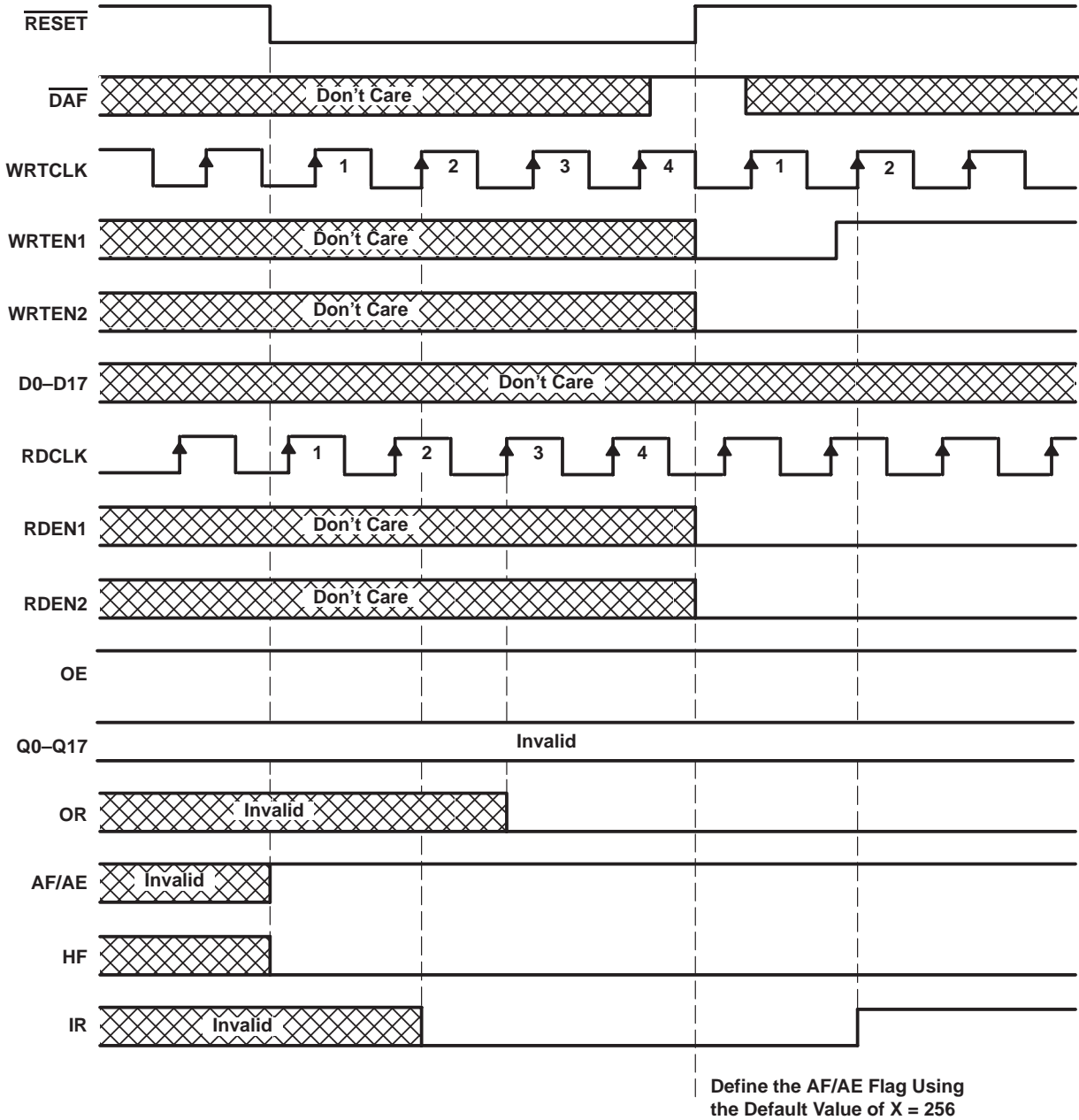
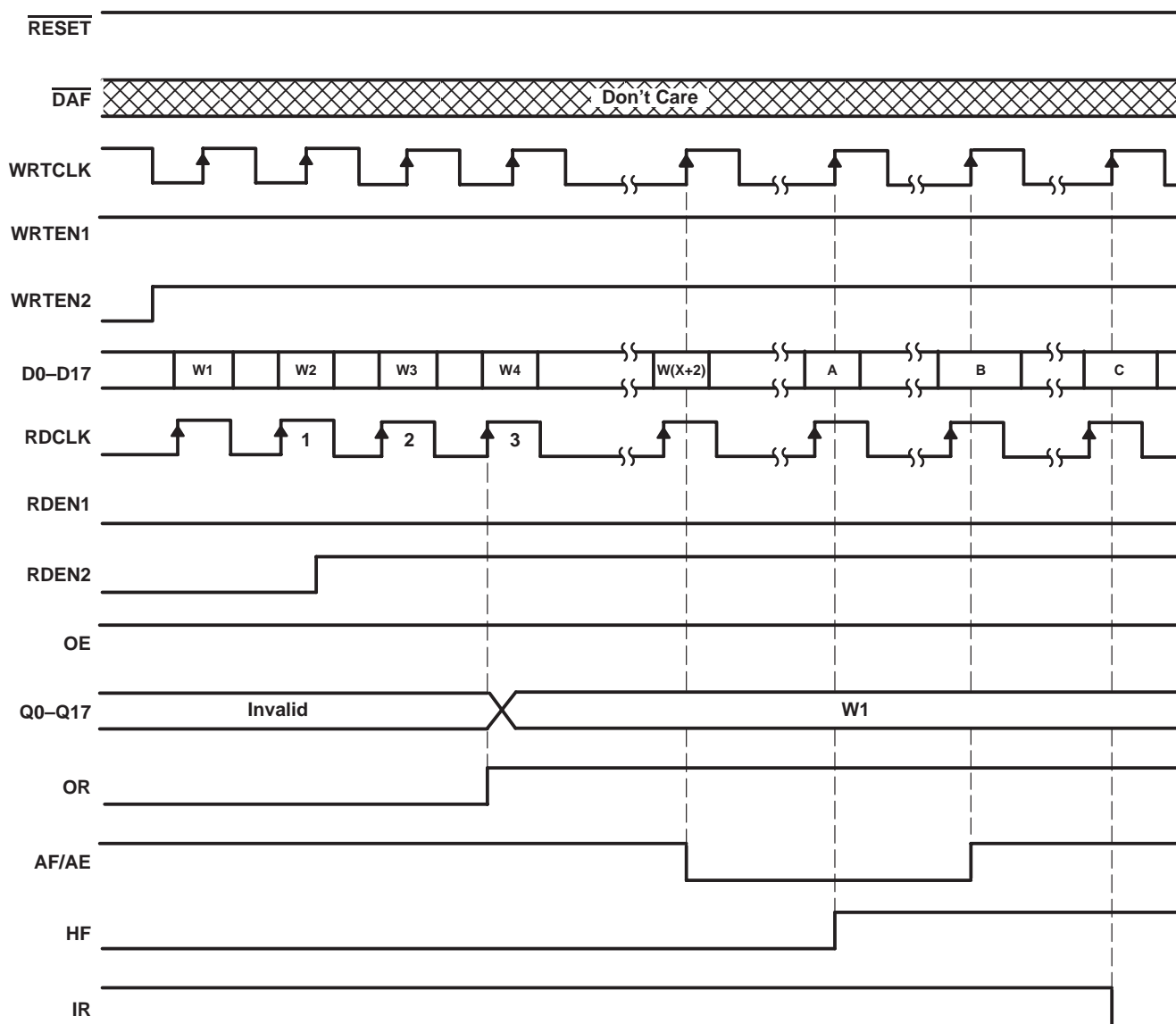


Figure 2. Reset Cycle: Define AF/AE Using the Default Value

SN74ACT7882
 2048 × 18
 CLOCKED FIRST-IN, FIRST-OUT MEMORY

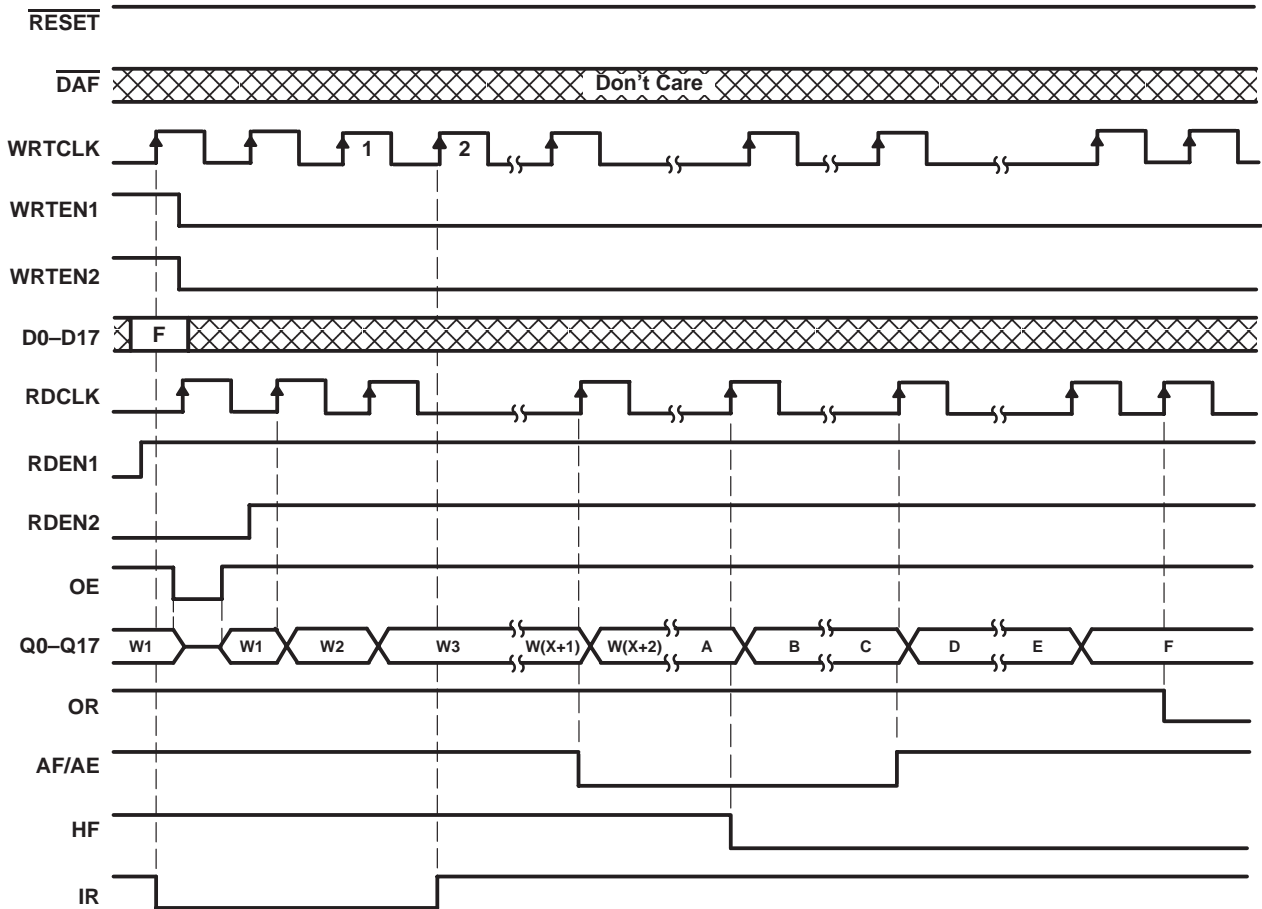
SCAS445C – JUNE 1994 – REVISED APRIL 1998



DATA-WORD NUMBERS FOR FLAG TRANSITIONS

TRANSITION WORD		
A	B	C
W1025	W(2049 - X)	W20495

Figure 3. Write



DATA-WORD NUMBERS FOR FLAG TRANSITIONS

TRANSITION WORD					
A	B	C	D	E	F
W1025	W1030	W(2048 - X)	W(2049 - X)	W2048	W2049

Figure 4. Read

absolute maximum ratings over operating free-air temperature†

Supply voltage range, V_{CC}	-0.5 V to 7 V
Input voltage range, V_I	-0.5 V to 7 V
Voltage range applied to a disabled 3-state output	-0.5 V to 5.5 V
Package thermal impedance, θ_{JA} (see Note 1): FN package	39°C/W
PN package	62°C/W
Storage temperature range, T_{stg}	-65°C to 150°C

† Stresses beyond those listed under “absolute maximum ratings” may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated under “recommended operating conditions” is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

NOTE 1: The package thermal impedance is calculated in accordance with JESD 51.

recommended operating conditions

	MIN	MAX	UNIT
V_{CC} Supply voltage	4.5	5.5	V
V_{IH} High-level input voltage	2		V
V_{IL} Low-level input voltage		0.8	V
I_{OH} High-level output current		-8	mA
I_{OL} Low-level output current		16	mA
T_A Operating free-air temperature	0	70	°C

electrical characteristics over recommended operating free-air temperature range (unless otherwise noted)

PARAMETER	TEST CONDITIONS	MIN	TYP‡	MAX	UNIT
V_{OH}	$V_{CC} = 4.5\text{ V}$, $I_{OH} = -8\text{ mA}$	2.4			V
V_{OL}	$V_{CC} = 4.5\text{ V}$, $I_{OL} = 16\text{ mA}$			0.5	V
I_I	$V_{CC} = 5.5\text{ V}$, $V_I = V_{CC}$ or 0			±5	µA
I_{OZ}	$V_{CC} = 5.5\text{ V}$, $V_O = V_{CC}$ or 0			±5	µA
$I_{CC}§$	$V_I = V_{CC} - 0.2\text{ V}$ or 0			400	µA
	One input at 3.4 V, Other inputs at V_{CC} or GND			1	mA
C_i	$V_I = 0$, $f = 1\text{ MHz}$		4		pF
C_o	$V_O = 0$, $f = 1\text{ MHz}$		8		pF

‡ All typical values are at $V_{CC} = 5\text{ V}$, $T_A = 25^\circ\text{C}$.

§ I_{CC} is tested with outputs open.



timing requirements over recommended ranges of supply voltage and operating free-air temperature (see Figures 1 through 5)

		'ACT7882-15		'ACT7882-20		'ACT7882-30		UNIT
		MIN	MAX	MIN	MAX	MIN	MAX	
f_{clock}	Clock frequency	67		50		33.4		MHz
t_w	Pulse duration	WRTCLK high		5	7	8.5		ns
		WRTCLK low		6	7	11		
		RDCLK high		5	7	8.5		
		RDCLK low		6	7	11		
		$\overline{\text{DAF}}$ high (default AF/AE value)		7	8	10		
t_{su}	Setup time	Data in (D0–D17) before WRTCLK \uparrow		5	5	5		ns
		WRTE1, WRTE2 high before WRTCLK \uparrow		4	5	5		
		OE, RDEN1, RDEN2 high before RDCLK \uparrow		4	5	5		
		Reset: $\overline{\text{RESET}}$ low before first WRTCLK \uparrow and RDCLK \uparrow \dagger		5	6	7		
		Define AF/AE: D0–D9 before $\overline{\text{DAF}}\downarrow$		5	5	5		
		Define AF/AE: $\overline{\text{DAF}}\downarrow$ before $\overline{\text{RESET}}\uparrow$		4	6	7		
		Define AF/AE (default): $\overline{\text{DAF}}$ high before $\overline{\text{RESET}}\uparrow$		4	5	5		
t_h	Hold time	Data in (D0–D17) after WRTCLK \uparrow		0	0	0		ns
		WRTE1, WRTE2 high after WRTCLK \uparrow		0	0	0		
		OE, RDEN1, RDEN2 high after RDCLK \uparrow		0	0	1		
		Reset: $\overline{\text{RESET}}$ low after fourth WRTCLK \uparrow and RDCLK \uparrow \dagger		0	0	0		
		Define AF/AE: D0–D9 after $\overline{\text{DAF}}\downarrow$		0	0	0		
		Define AF/AE: $\overline{\text{DAF}}$ low after $\overline{\text{RESET}}\uparrow$		0	0	0		
		Define AF/AE (default): $\overline{\text{DAF}}$ high after $\overline{\text{RESET}}\uparrow$		0	0	0		

\dagger To permit the clock pulse to be utilized for reset purposes

switching characteristics over recommended ranges of supply voltage and operating free-air temperature, $C_L = 50$ pF (unless otherwise noted) (see Figure 5)

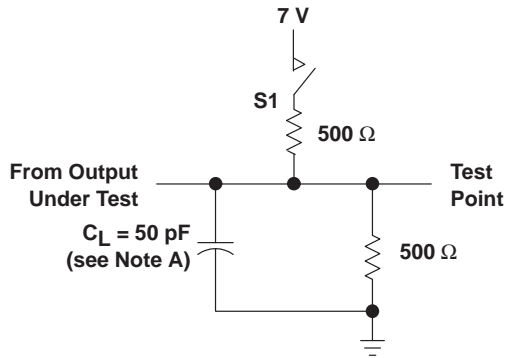
PARAMETER	FROM (INPUT)	TO (OUTPUT)	'ACT7882-15		'ACT7882-20		'ACT7882-30		UNIT
			MIN	MAX	MIN	MAX	MIN	MAX	
f_{max}	WRTCLK or RDCLK		67		50		33.4		MHz
t_{pd}	RDCLK \uparrow	Any Q	3	12	3	13	3	18	ns
$t_{\text{pd}}\ddagger$	RDCLK \uparrow	Any Q							ns
t_{pd}	WRTCLK \uparrow	IR	2	8	2	9.5	2	12	
	RDCLK \uparrow	OR	2	8	2	9.5	2	12	
	WRTCLK \uparrow	AF/AE	6	17	6	19	6	22	
RDCLK \uparrow	6		17	6	19	6	22		
t_{PLH}	WRTCLK \uparrow	HF	6	14	6	17	6	21	ns
t_{PHL}	RDCLK \uparrow	HF	6	14	6	17	6	21	ns
t_{PLH}	$\overline{\text{RESET}}\downarrow$	AF/AE	3	12	3	17	3	21	ns
t_{PHL}	$\overline{\text{RESET}}\downarrow$	HF	3	14	3	19	3	23	ns
t_{en}	OE	Any Q	2	9	2	11	2	11	ns
t_{dis}	OE	Any Q	2	10	2	14	2	14	ns

\ddagger This parameter is measured with $C_L = 30$ pF (see Figure 6).

operating characteristics, $V_{CC} = 5\text{ V}$, $T_A = 25^\circ\text{C}$

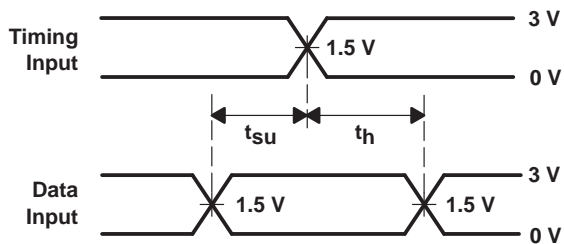
PARAMETER	TEST CONDITIONS	TYP	UNIT
C_{pd} Power dissipation capacitance per 1K bits	$C_L = 50\text{ pF}$, $f = 5\text{ MHz}$	65	pF

PARAMETER MEASUREMENT INFORMATION

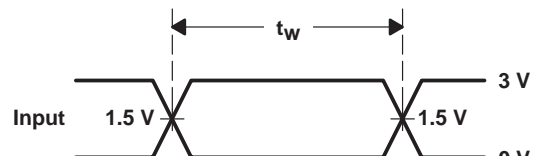


LOAD CIRCUIT

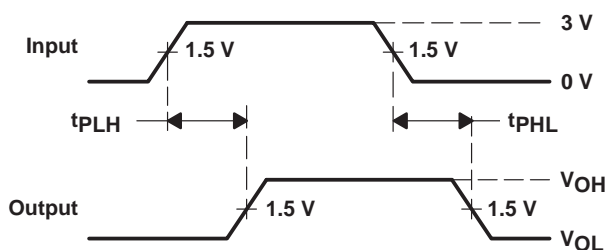
PARAMETER	S1	
t_{en}	tPZH	Open
	tPZL	Closed
t_{dis}	tPHZ	Open
	tPLZ	Closed
t_{pd}	tPLH	Open
	tPHL	Open



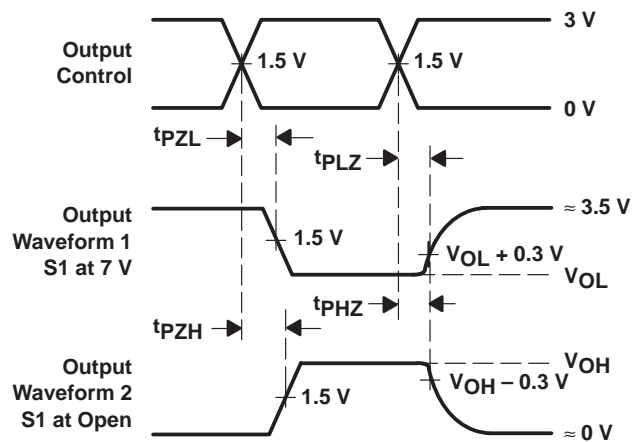
VOLTAGE WAVEFORMS SETUP AND HOLD TIMES



VOLTAGE WAVEFORMS PULSE DURATION



VOLTAGE WAVEFORMS PROPAGATION DELAY TIMES



VOLTAGE WAVEFORMS ENABLE AND DISABLE TIMES

NOTE A: C_L includes probe and jig capacitance.

Figure 5. Load Circuit and Voltage Waveforms

TYPICAL CHARACTERISTICS

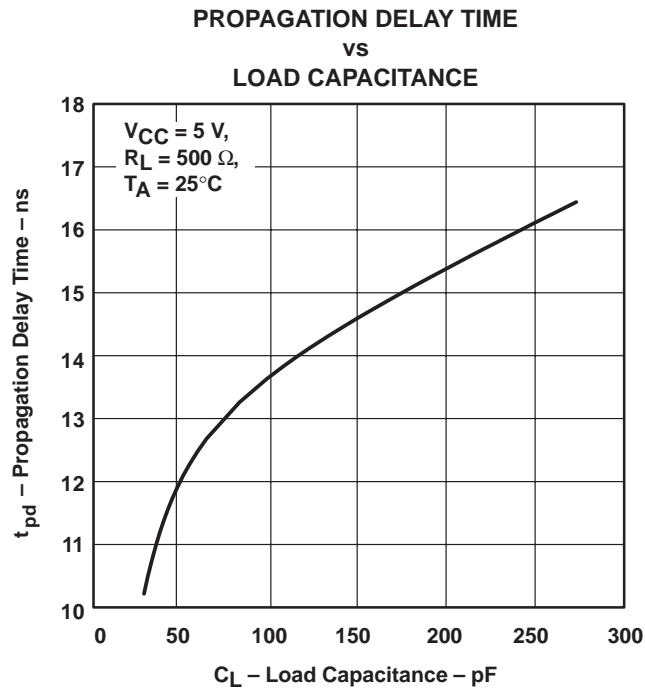


Figure 6

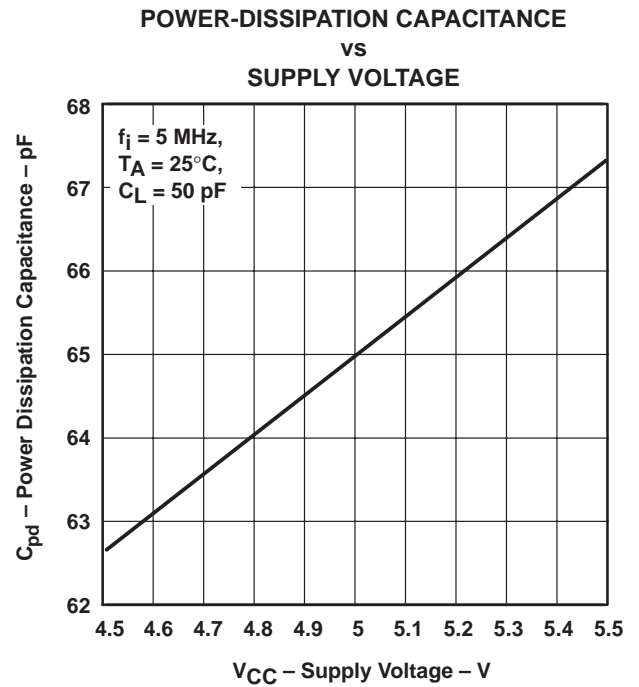


Figure 7

APPLICATION INFORMATION

expanding the SN74ACT7882

The SN74ACT7882 is expandable in both word width and word depth. Word-depth expansion is accomplished by connecting the devices in series such that data flows through each device in the chain. Figure 8 shows two SN74ACT7882 devices configured for depth expansion. The common clock between the devices can be tied to either the write clock (WRTCLK) of the first device or the read clock (RDCLK) of the last device. The output-ready (OR) flag of the previous device and the input-ready (IR) flag of the next device maintain data flow to the last device in the chain whenever space is available.

Figure 9 is an example of two SN74ACT7882 devices in word-width expansion. Width expansion is accomplished by simply connecting all common control signals between the devices and creating composite IR and OR signals. The almost-full/almost-empty (AF/AE) flag and half-full (HF) flag can be sampled from any one device. Depth expansion and width expansion can be used together.

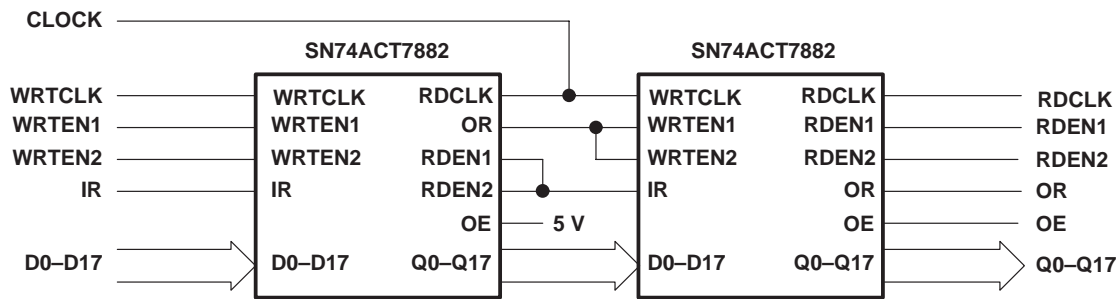


Figure 8. Word-Depth Expansion: 4096 × 18 Bits

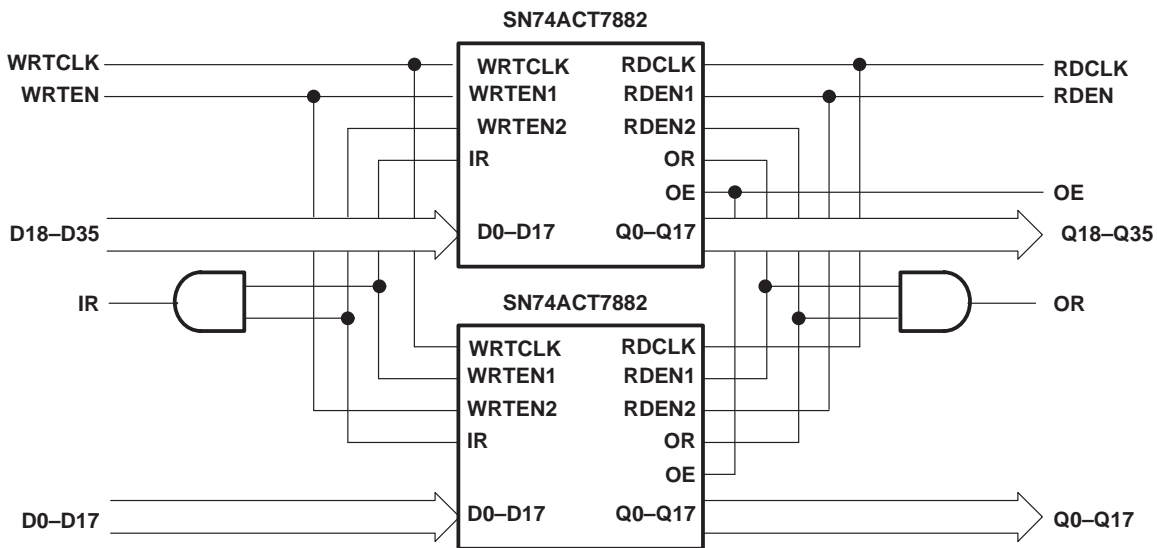


Figure 9. Word-Width Expansion: 2048 × 36 Bits

PACKAGING INFORMATION

Orderable Device	Status ⁽¹⁾	Package Type	Package Drawing	Pins	Package Qty	Eco Plan ⁽²⁾	Lead/Ball Finish	MSL Peak Temp ⁽³⁾
SN74ACT7882-15FN	ACTIVE	PLCC	FN	68	18	TBD	CU	Level-3-220C-168 HR
SN74ACT7882-15PN	ACTIVE	LQFP	PN	80	119	TBD	CU NIPDAU	Level-3-220C-168 HR
SN74ACT7882-20FN	ACTIVE	PLCC	FN	68	18	TBD	CU	Level-3-220C-168 HR
SN74ACT7882-20PN	ACTIVE	LQFP	PN	80	119	TBD	CU NIPDAU	Level-3-220C-168 HR
SN74ACT7882-30FN	ACTIVE	PLCC	FN	68	18	TBD	CU	Level-3-220C-168 HR
SN74ACT7882-30PN	ACTIVE	LQFP	PN	80	119	TBD	CU NIPDAU	Level-3-220C-168 HR

⁽¹⁾ The marketing status values are defined as follows:

ACTIVE: Product device recommended for new designs.

LIFEBUY: TI has announced that the device will be discontinued, and a lifetime-buy period is in effect.

NRND: Not recommended for new designs. Device is in production to support existing customers, but TI does not recommend using this part in a new design.

PREVIEW: Device has been announced but is not in production. Samples may or may not be available.

OBSELETE: TI has discontinued the production of the device.

⁽²⁾ Eco Plan - The planned eco-friendly classification: Pb-Free (RoHS) or Green (RoHS & no Sb/Br) - please check <http://www.ti.com/productcontent> for the latest availability information and additional product content details.

TBD: The Pb-Free/Green conversion plan has not been defined.

Pb-Free (RoHS): TI's terms "Lead-Free" or "Pb-Free" mean semiconductor products that are compatible with the current RoHS requirements for all 6 substances, including the requirement that lead not exceed 0.1% by weight in homogeneous materials. Where designed to be soldered at high temperatures, TI Pb-Free products are suitable for use in specified lead-free processes.

Green (RoHS & no Sb/Br): TI defines "Green" to mean Pb-Free (RoHS compatible), and free of Bromine (Br) and Antimony (Sb) based flame retardants (Br or Sb do not exceed 0.1% by weight in homogeneous material)

⁽³⁾ MSL, Peak Temp. -- The Moisture Sensitivity Level rating according to the JEDEC industry standard classifications, and peak solder temperature.

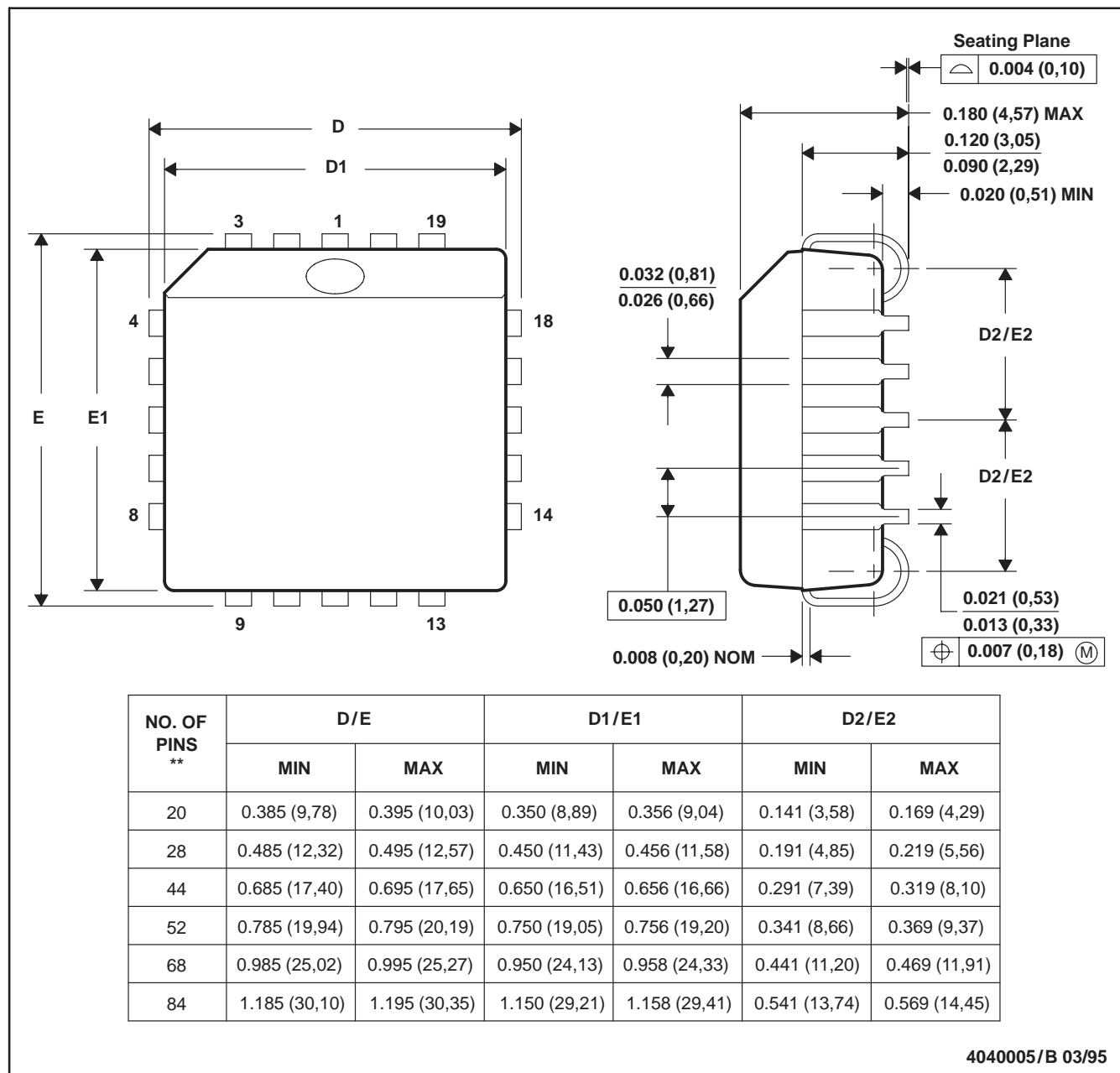
Important Information and Disclaimer:The information provided on this page represents TI's knowledge and belief as of the date that it is provided. TI bases its knowledge and belief on information provided by third parties, and makes no representation or warranty as to the accuracy of such information. Efforts are underway to better integrate information from third parties. TI has taken and continues to take reasonable steps to provide representative and accurate information but may not have conducted destructive testing or chemical analysis on incoming materials and chemicals. TI and TI suppliers consider certain information to be proprietary, and thus CAS numbers and other limited information may not be available for release.

In no event shall TI's liability arising out of such information exceed the total purchase price of the TI part(s) at issue in this document sold by TI to Customer on an annual basis.

FN (S-PQCC-J**)

PLASTIC J-LEADED CHIP CARRIER

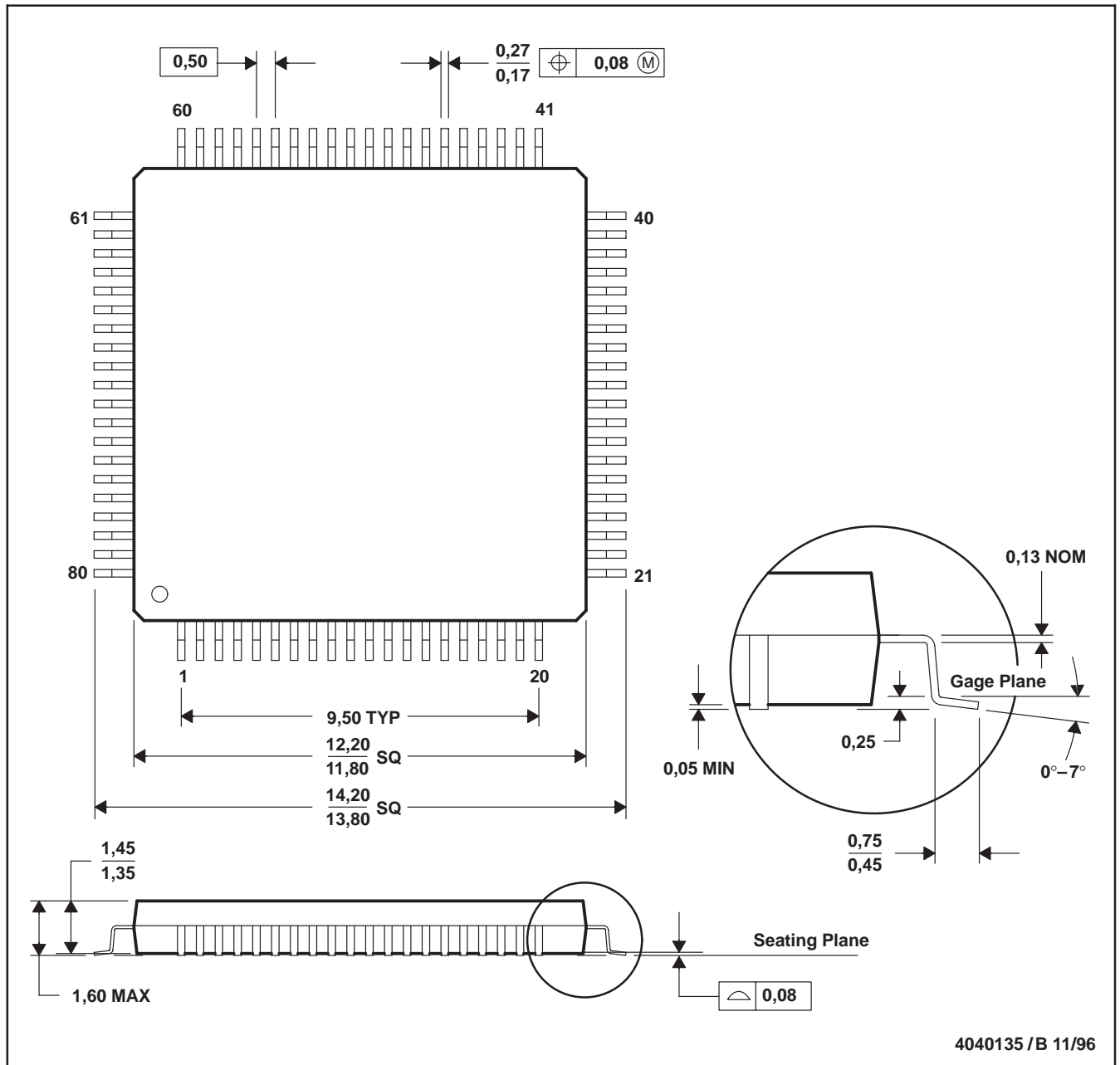
20 PIN SHOWN



- NOTES: A. All linear dimensions are in inches (millimeters).
 B. This drawing is subject to change without notice.
 C. Falls within JEDEC MS-018

PN (S-PQFP-G80)

PLASTIC QUAD FLATPACK



- NOTES: A. All linear dimensions are in millimeters.
 B. This drawing is subject to change without notice.
 C. Falls within JEDEC MS-026

IMPORTANT NOTICE

Texas Instruments Incorporated and its subsidiaries (TI) reserve the right to make corrections, modifications, enhancements, improvements, and other changes to its products and services at any time and to discontinue any product or service without notice. Customers should obtain the latest relevant information before placing orders and should verify that such information is current and complete. All products are sold subject to TI's terms and conditions of sale supplied at the time of order acknowledgment.

TI warrants performance of its hardware products to the specifications applicable at the time of sale in accordance with TI's standard warranty. Testing and other quality control techniques are used to the extent TI deems necessary to support this warranty. Except where mandated by government requirements, testing of all parameters of each product is not necessarily performed.

TI assumes no liability for applications assistance or customer product design. Customers are responsible for their products and applications using TI components. To minimize the risks associated with customer products and applications, customers should provide adequate design and operating safeguards.

TI does not warrant or represent that any license, either express or implied, is granted under any TI patent right, copyright, mask work right, or other TI intellectual property right relating to any combination, machine, or process in which TI products or services are used. Information published by TI regarding third-party products or services does not constitute a license from TI to use such products or services or a warranty or endorsement thereof. Use of such information may require a license from a third party under the patents or other intellectual property of the third party, or a license from TI under the patents or other intellectual property of TI.

Reproduction of information in TI data books or data sheets is permissible only if reproduction is without alteration and is accompanied by all associated warranties, conditions, limitations, and notices. Reproduction of this information with alteration is an unfair and deceptive business practice. TI is not responsible or liable for such altered documentation.

Resale of TI products or services with statements different from or beyond the parameters stated by TI for that product or service voids all express and any implied warranties for the associated TI product or service and is an unfair and deceptive business practice. TI is not responsible or liable for any such statements.

Following are URLs where you can obtain information on other Texas Instruments products and application solutions:

Products		Applications	
Amplifiers	amplifier.ti.com	Audio	www.ti.com/audio
Data Converters	dataconverter.ti.com	Automotive	www.ti.com/automotive
DSP	dsp.ti.com	Broadband	www.ti.com/broadband
Interface	interface.ti.com	Digital Control	www.ti.com/digitalcontrol
Logic	logic.ti.com	Military	www.ti.com/military
Power Mgmt	power.ti.com	Optical Networking	www.ti.com/opticalnetwork
Microcontrollers	microcontroller.ti.com	Security	www.ti.com/security
		Telephony	www.ti.com/telephony
		Video & Imaging	www.ti.com/video
		Wireless	www.ti.com/wireless

Mailing Address: Texas Instruments
Post Office Box 655303 Dallas, Texas 75265

Looking for pricing, stock, or lifecycle information?

Click below to explore more details on WIN SOURCE:

 [View SN74ACT7882-30PN on WIN SOURCE](#)

 [Texas Instruments](#) Information

Optimize Your Supply Chain with WIN SOURCE Solutions

-  Global Sourcing Solution
-  Obsolete Management
-  Cost Control Management
-  Shortage Management
-  Alternative Solution
-  Excess Inventory Management